

3. PREPARATION AND EXAMINATION OF SPECIMENS

(1) equatorial setting, whereby a particular reciprocal-lattice plane is aligned perpendicular to a given direction. This setting is equivalent to bringing a direct-lattice vector (perpendicular to the reciprocal-lattice plane) parallel to the given direction;

(2) azimuthal setting, whereby a reciprocal-lattice vector, in the equatorial plane, is positioned to make a given angle with the plane containing the given direction and the X-ray beam.

In the rotation or oscillation methods, the given direction is the camera rotation axis, but precession geometry requires a direct-lattice vector to be aligned along the X-ray beam. This section will briefly discuss:

- (1) equatorial setting using a rotation camera;
- (2) setting and orientation using stationary-crystal methods;
- (3) rotation geometry setting for crystals with large unit cells;
- (4) diffractometer setting considerations.

Specialized methods for orientating and cutting large single crystals are not covered, but two-axis goniometers have been designed by Denne (1971*a*) and Shaham (1982), and methods for cutting single crystals along any desired direction have been reported by Campos, Cardoso & Caticha-Ellis (1983) and Desai & Bhatt (1984).

3.4.2.2. Preliminary considerations

Prior to the commencement of the setting process, it is useful to align the crystal optically so that prominent morphological features bear fixed geometrical relationships with the component parts of the goniometer head. Thus, a prismatic crystal could be aligned with its longest axis parallel to the mount, but in addition with a face perpendicular to the rotation axis of one of the goniometer arcs. Many modern goniometer heads have a rotatable component to which the crystal mount can be fixed, and judicious use of this facility can considerably simplify the setting process. This may be particularly important for crystals that are very sensitive to X-radiation. It is also useful if the arc readings on the goniometer head are equal or close to zero. Large deviations away from the zero positions can lead to mechanical collision with other parts of the camera (*e.g.* the layer-line screens of a Weissenberg camera), or in extreme cases to interference with the primary or diffracted X-ray beams. If the crystal mount is fixed to the goniometer head with wax or plasticine, this can often be achieved by manual manipulation of the mount and the wax. The use of less-pliable adhesives requires careful monitoring during the hardening process. Although the detailed alignment will depend on the geometry of the recording device, care taken at the mounting stage will always result in increased efficiency in setting. Sensible orientation of the goniometer head on the camera may also lead to increased efficiency, and it is often useful to start with the axes of the goniometer arcs perpendicular and parallel to the X-ray beam.

3.4.2.3. Equatorial setting using a rotation camera

Methods for equatorial setting are well described by Jeffery (1971). The aim is to identify reciprocal-lattice layer lines from X-ray oscillation photographs and, by measuring the degree and directions of curvature of the zero-layer line, to adjust the crystal setting until the layer-line patterns are made perpendicular to the rotation axis, *i.e.* the crystal lattice vector perpendicular to these reciprocal-lattice layers lies parallel to the rotation axis. For crystals of well defined morphology, initial alignment of a crystal lattice vector with the rotation axis can be achieved optically, often to within a degree. For setting errors of less than 5°, reciprocal-lattice layer lines should be readily identifiable on X-ray oscillation diffraction patterns. The use of unfiltered X-radiation often assists in this regard (as well as reducing

exposure times), and a device described by Kulpe (Kulpe, 1963; Kulpe & Dornberger-Schiff, 1965) may prove useful in the identification of the zero-layer equatorial pattern on photographic films.

For accurate final setting, a general 'double-oscillation' method such as that of Weisz & Cole as modified by Davies (Jeffery, 1971) is preferred, although Suh, Suh, Ko, Aoki & Yamazaki (1988) have provided a rationale for adjustment of both goniometer arcs simultaneously from a 'single-oscillation' photograph. With the 'double-oscillation' technique, two single oscillations, separated by a φ reading of 180°, are recorded on the same image, but with significantly different exposure times, so that the patterns are related by a mirror plane and are readily distinguishable. The goniometer arcs are placed at 45° to the X-ray beam. Measurements of the relative displacements of the two patterns at the $2\theta = 90^\circ$ position on the image readily yield corrections to both goniometer-head arcs. No translational movement of the film cassette is required, but the crystal must diffract to at least a θ angle of 45°. Hanson (1981) has devised a technique suitable for a Weissenberg camera that is a combination of double oscillation with displacements and measurements at low- 2θ angles. This method is particularly suitable for crystals with large unit cells.

In the case where layer lines are not readily locatable, but the crystal unit-cell dimensions are known, Jeffery (1971) also describes an equatorial setting technique that relies on the indexing of at least three low-angle Laue streaks.

Okasaki & Soejima (1986) have described two simple goniometer attachments that may prove useful for crystals that have been mounted so that the angular movements required to achieve setting exceed the range commonly available on goniometer heads.

3.4.2.4. Precession geometry setting with moving-crystal methods

Methods of setting crystals so that a crystal lattice vector lies along the X-ray beam have been fully described by Buerger (1964). Optical alignment precedes small-angle (typically 2–5°) precession photographs taken with unfiltered radiation. The use of a screen with a central hole may assist the identification of the outer ends of the white-radiation streaks on the zero-layer pattern by preventing the recording of the upper-layer patterns. The deviation of the zero-layer pattern from cylindrical symmetry about the direct beam leads to the measurement of simultaneous corrections for the spindle angle and goniometer-head arcs. These adjustments are particularly easy if the goniometer-head arcs are perpendicular and parallel to the X-ray beam, and both arcs read zero. Reider (1975) has proposed an approximate stereographic method of making appropriate corrections when these ideal conditions are not fulfilled. Where optical alignment is not possible, or recognition of a zero-layer pattern is difficult, reciprocal space can be systematically explored by taking a series of small-angle precession photographs at regular intervals (*e.g.* 15°) around the spindle axis until a suitable zero-layer pattern is found. In such cases, and particularly for non-orthogonal crystal systems, the use of the complementary rotation technique is recommended (see Subsection 3.4.2.3).

In the final alignment when the crystal lattice vector is parallel to the X-ray beam, it is also desirable to have a reciprocal axis parallel to the spindle axis. With this combined setting, it is possible to survey the whole of reciprocal space (to a θ limit equal to the maximum precession angle mechanically available) with one mounting of the crystal.